

# Simulations of Micro-electrode and Neuron Interfaces Enable Long-term and High Fidelity Recordings

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**Introduction:** While the use of micro-electrodes has advanced long-term recordings of single neuron activity (Figure 1), their low sealing resistance (defined as the resistance that restricts current leakage through the liquid gap between a neuron and an electrode in a lab on a chip device) considerably decreases the signal resolution. Here we report simulations of sealing resistance from a novel micro-electrode with nano-edges that permits long-term ( $\geq 1$  month) and high fidelity recordings.

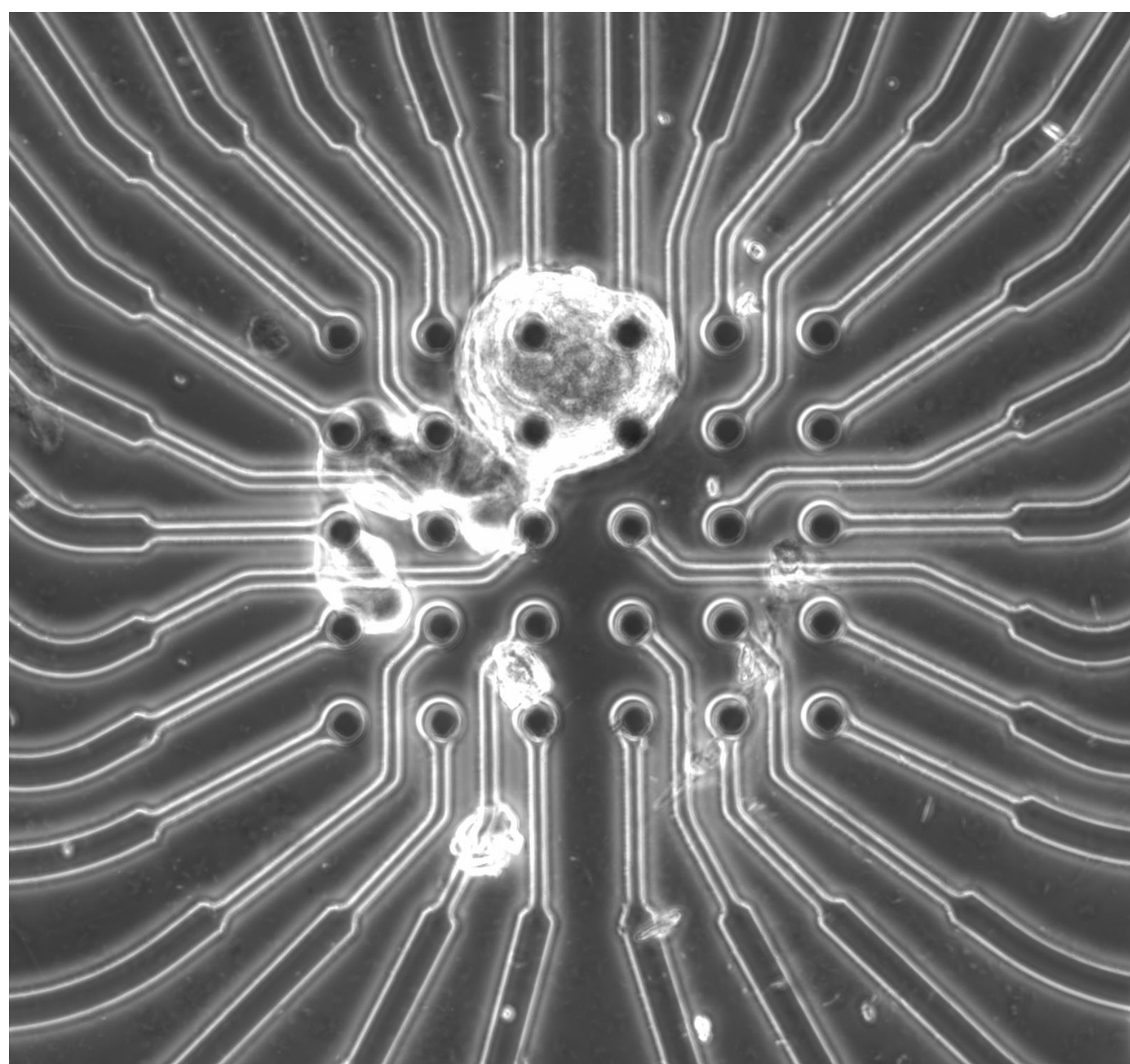


Figure 1. Single invertebrate cell on a multi electrode array

**Computational Methods:** We improved on a previous neuron-electrode interface model [1-2] using the *Electric Currents* module in COMSOL Multiphysics (COMSOL Inc., Burlington MA) (Figure 2) to determine the effect of the nano-edge on the sealing resistance (modeled values given in Table 1). While a standard free tetrahedral mesh was used for the neuron, a free triangular swept mesh was implemented to mesh the smaller portions of the simulation (thin gold electrode and nano-edge).

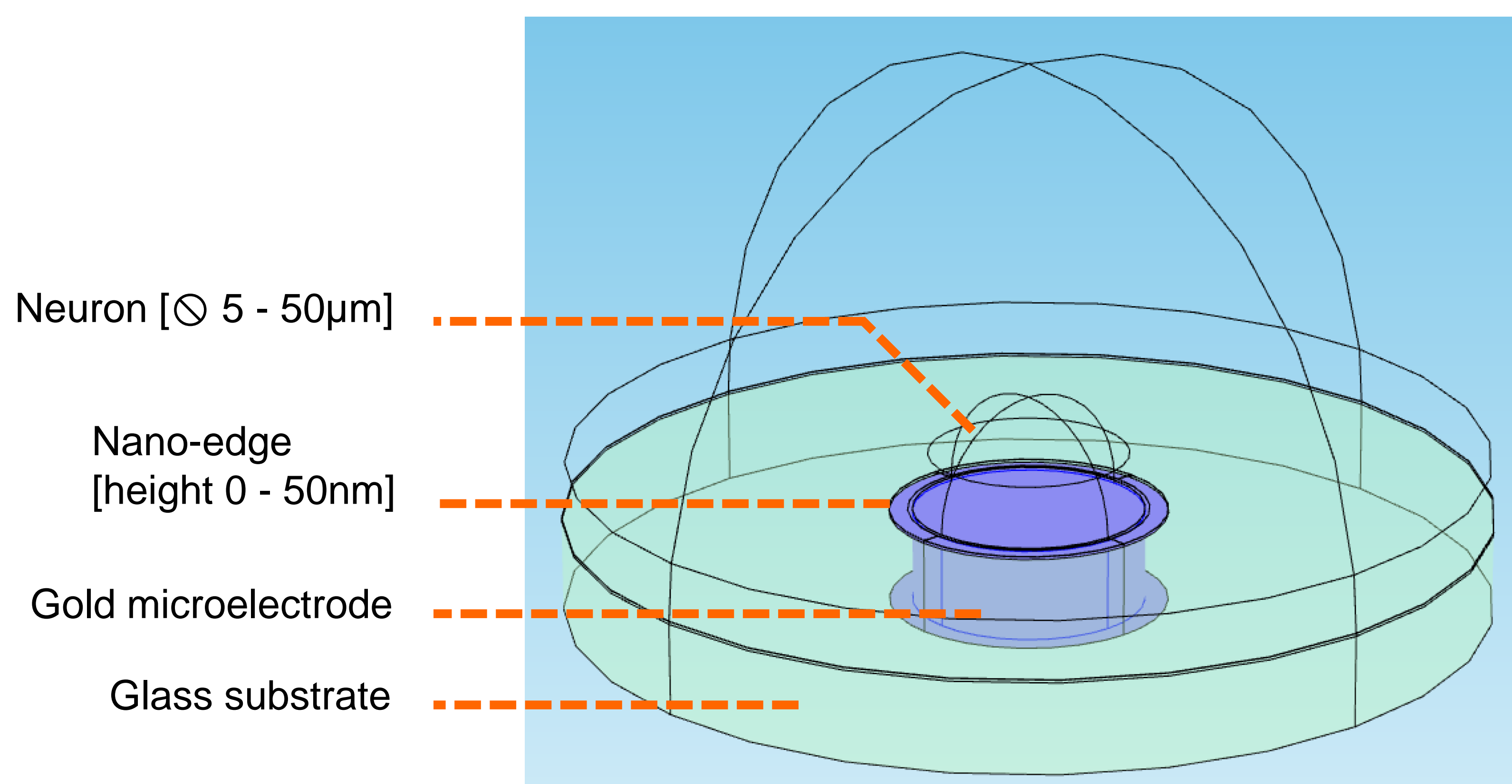


Figure 2. Modeled domains and variation ranges

Materials	Electrical Conductivity	Relative Permittivity
Gold electrode	45.6e6 [2]	6.9 [2]
Cell Membrane	7.93e-8 [3]	5.6470 [4]
Extracellular Fluid	0.84 [5]	80 [5]
Intracellular Fluid	0.68 [5]	80 [5]
Dielectric nano-edge	3.5e-15 [6]	4.1 [6]

Table 1. Values of electrical conductivity and relative permittivity

**Results:** The sealing resistance values varied significantly (from 0.66M $\Omega$  to 8.71M $\Omega$ , Figures 3 and 4) depending on the morphologic changes that were simulated by altering the height of the nano-edge and the size of the simulated neuron. In comparison, traditional micro-electrodes with no nano-edge only create a sealing resistance of  $1.0 \pm 0.2$  M $\Omega$ . A higher signal-to-noise ratio was experimentally verified with fabricated devices.

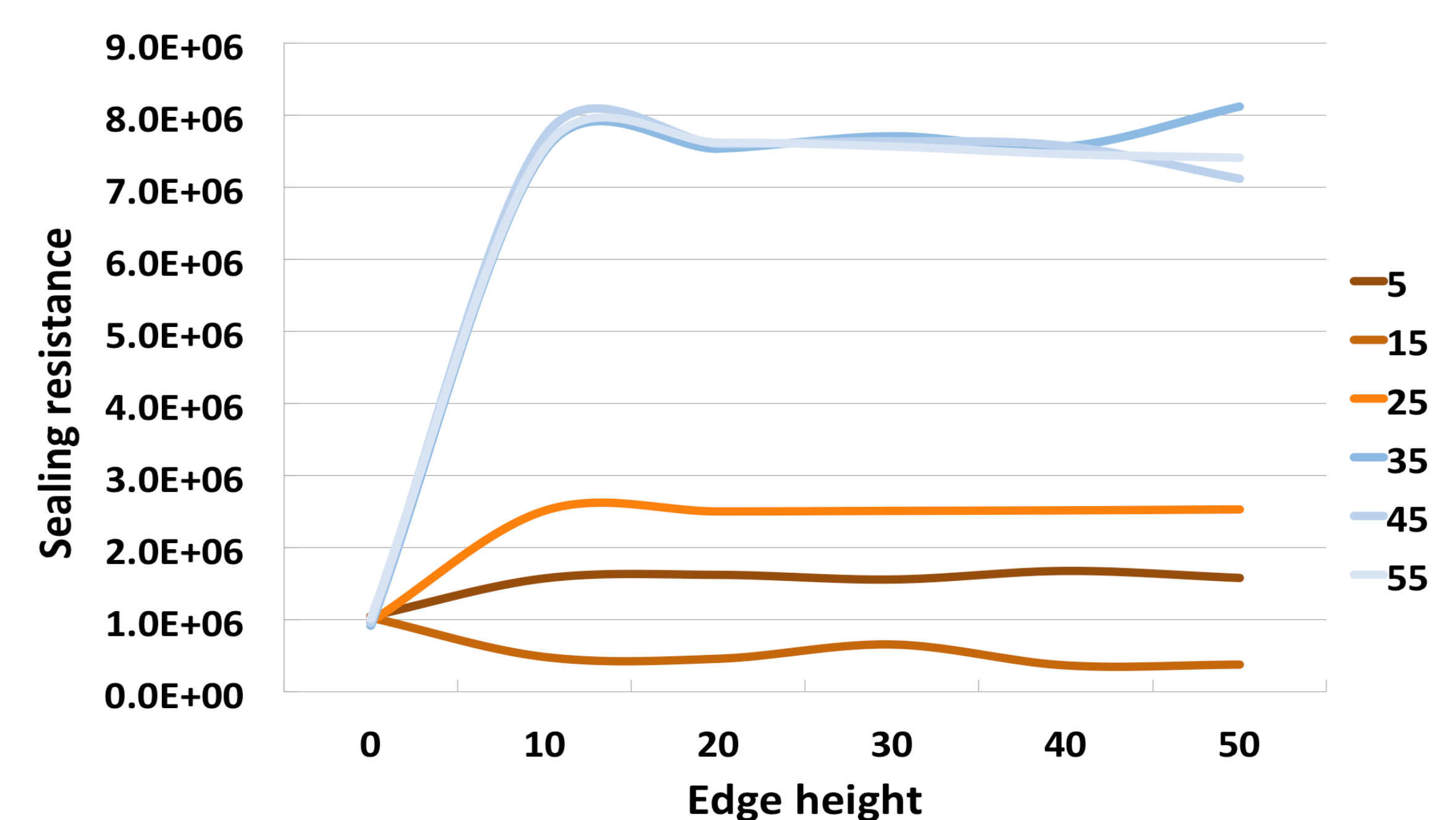


Figure 3. Variation of the sealing resistance for different cell diameters (electrode's diameter fixed at 30 $\mu$ m)

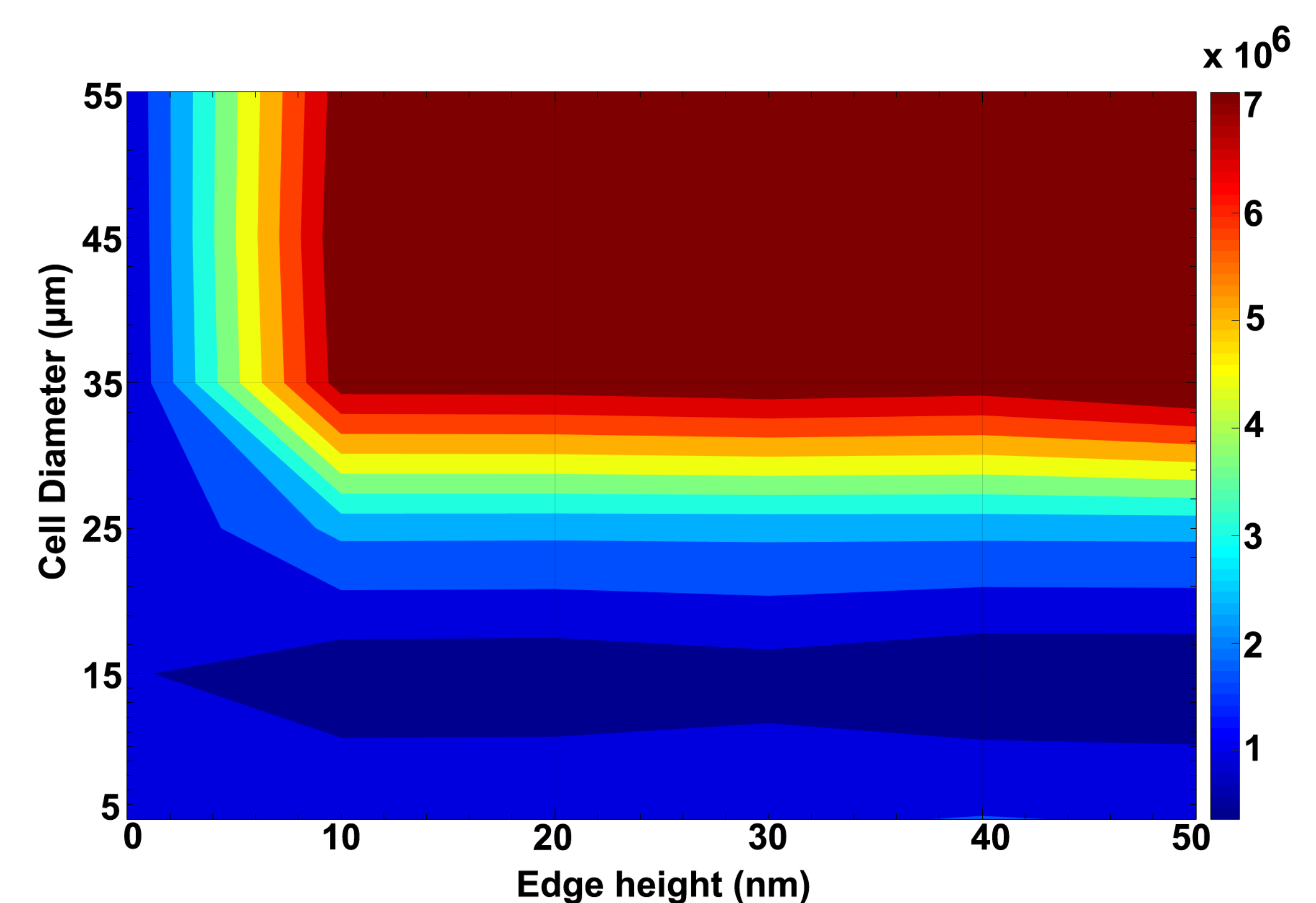


Figure 4. Variation of the sealing resistance depending on the cell diameter and the edge height (electrode's diameter fixed at 30 $\mu$ m)

**Conclusions:** The simulations support that our newly developed micro-electrodes with nano-edges permit a significantly higher sealing resistance that in turn allows for a better signal-to-noise ratio. These effects have been verified experimentally, and will now enable better understanding of brain function, pathological neural conditions to better develop bionic hybrids and drug discovery lab on a chip devices.

## References:

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